


SANYO Semiconductors

DATA SHEET

LA75676M — Monolithic Linear IC For TV and VCR Products IF Signal Processor (VIF+SIF)

Overview

The LA75676M is a VIF/SIF IC that supports NTSC intercarrier reception and adopts a semi-adjustment-free design. It is provided in the MFP24S (300mil, 1.0mm lead pitch) package, which is appropriate for miniature 2-in-1 tuner products. In the VIF block, it adopts a design that uses AFT adjustment to obviate the need for VCO adjustment, and thus can simplify the adjustment steps required in end product manufacturing. It uses a PLL technique for FM detection. It features the 5V supply voltage appropriate for multimedia products. In addition, it achieves superb audio quality by incorporating a buzz canceller that suppresses Nyquist buzzing.

Functions

- VIF block: VIF amplifier, buzz canceller, PLL detector, IF AGC, RF AGC, AFT, and an equalizer amplifier
- SIF block: Limiter amplifier, PLL FM detector

Specifications

Maximum Ratings at Ta = 25°C

Parameter	Symbol	Conditions	Ratings	Unit
Maximum supply voltage	V _{CC} max		6	V
Circuit voltage	V13, V17		V _{CC}	V
Circuit current	I6		-3	mA
	I10		-10	mA
	I24		-2	mA
Allowable power dissipation	Pd max	Ta ≤ 70°C * Mounted on a board	400	mW
Operating temperature	Topr		-20 to +70	°C
Storage temperature	Tstg		-55 to +150	°C

* When mounted on a 114.3×76.1×1.6mm³, glass epoxy board.

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LA75676M

Operating Conditions at Ta = 25°C

Parameter	Symbol	Conditions	Ratings	Unit
Recommended supply voltage	V _{CC}		5	V
Operating supply voltage range	V _{CC op}		4.5 to 5.5	V

Electrical Characteristics at Ta = 25°C, V_{CC} = 5V, fp = 45.75MHz

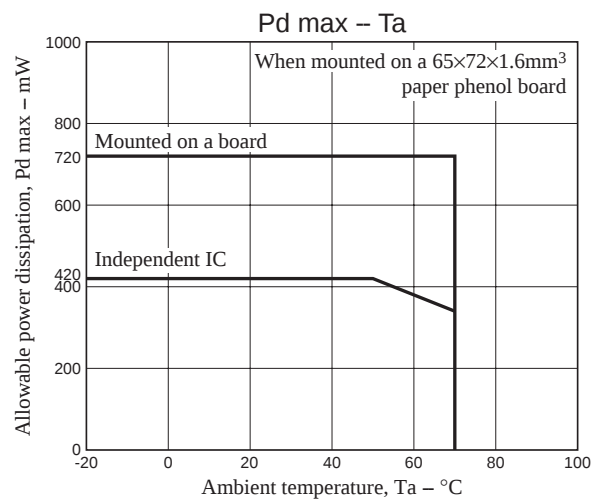
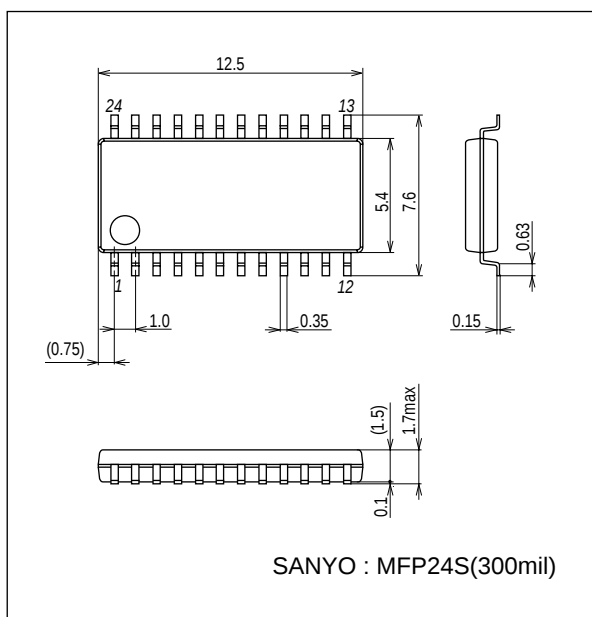
Parameter	Symbol	Conditions	Ratings			Unit
			min	typ	max	
[VIF Block]						
Circuit current	I _S		32	40	48	mA
Maximum RF AGC voltage	V14H		V _{CC} -0.5	V _{CC}		V
Minimum RF AGC voltage	V14L			0	0.5	V
Input sensitivity	V _i	S1 = OFF	32	38	44	dBμV
AGC range	GR		58	63		dB
Maximum allowable input	V _i max		95	100		dBμV
Video output voltage (no input)	V ₆		3.5	3.8	4.1	V
Sync signal tip voltage	V6tip		0.9	1.2	1.5	V
Video output level	V _O		1.7	2	2.3	Vp-p
Black noise threshold voltage	VBTH		0.5	0.8	1.1	V
Black noise clamp voltage	VBCL		1.6	1.9	2.2	V
Video signal-to-noise ratio	S/N		48	52		dB
C-S beating	IC-S		38	43		dB
Frequency characteristics	f _c	6MHz	-3	-1.5		dB
Differential gain	DG			3	6.5	%
Differential phase	DP			3	5	°C
AFT voltage (no signal)	V13		2.0	2.5	3.0	V
Maximum AFT voltage	V13H		4.0	4.4	5.0	V
Minimum AFT voltage	V13L			0.18	1.0	V
AFT detection sensitivity	S _f		28	40	52	mV/kHz
VIF input resistance	R _i	45.75MHz		1.5		kΩ
VIF input capacitance	C _i	45.75MHz		3		pF
APC pull-in range (U)	f _{pu}		1.3	2.0		MHz
APC pull-in range (L)	f _{pl}			-2.0	-1.4	MHz
AFT tolerance frequency 1	d _{fa1}		-150	0	+150	kHz
VCO 1 maximum range (U)	d _{fu}		1.5	2.0		MHz
VCO 1 maximum range (L)	d _{fl}			-2.0	-1.5	MHz
VCO control sensitivity	B		1.3	2.7	5.4	kHz/mV
[SIF BLOCK]						
Limiting sensitivity	V _{li} (lim)		39	45	51	dBμV
FM detection output voltage*	V _O (FM)	4.5MHz ±25kHz	400	520	660	mVrms
AMR	AMR		50	60		dB
Total harmonic distortion	THD			0.3	0.8	%
SIF signal-to-noise ratio	S/N (FM)		59	64		dB
4.5MHz output level	V _{sout}	SIF IN 80dBμV	87	94	101	dBμV

* : If a wider FM detection output dynamic range is required, insert a resistor and capacitor in series between pin 23 and ground to adjust the level.

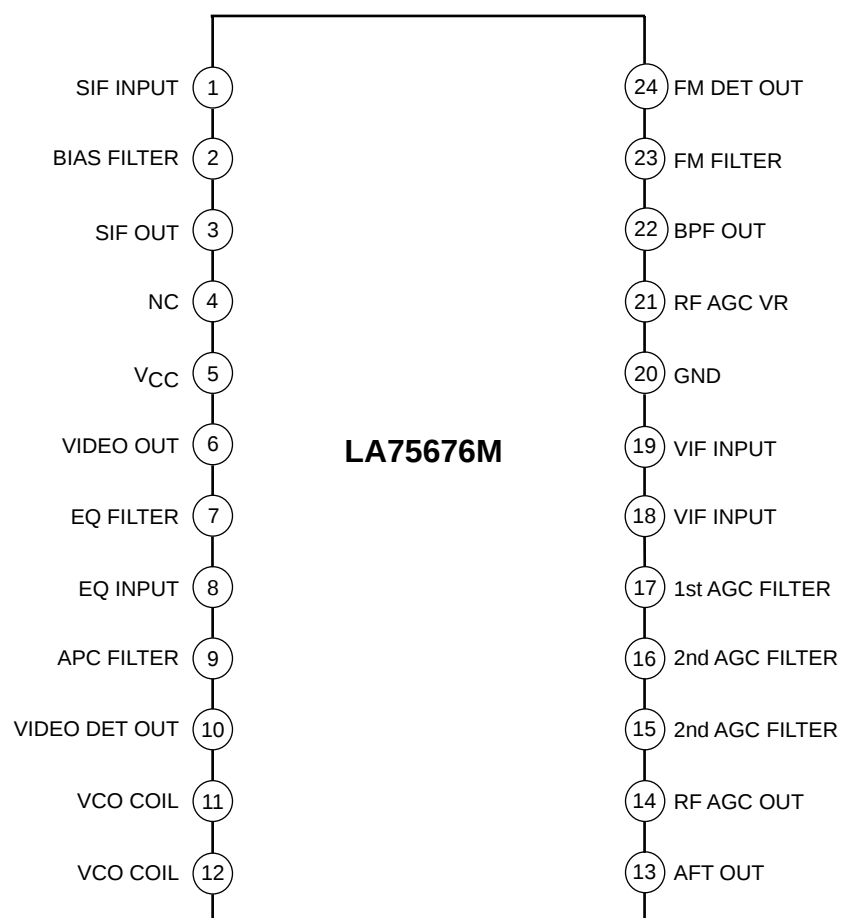
Package Dimensions

unit : mm (typ)

3112B

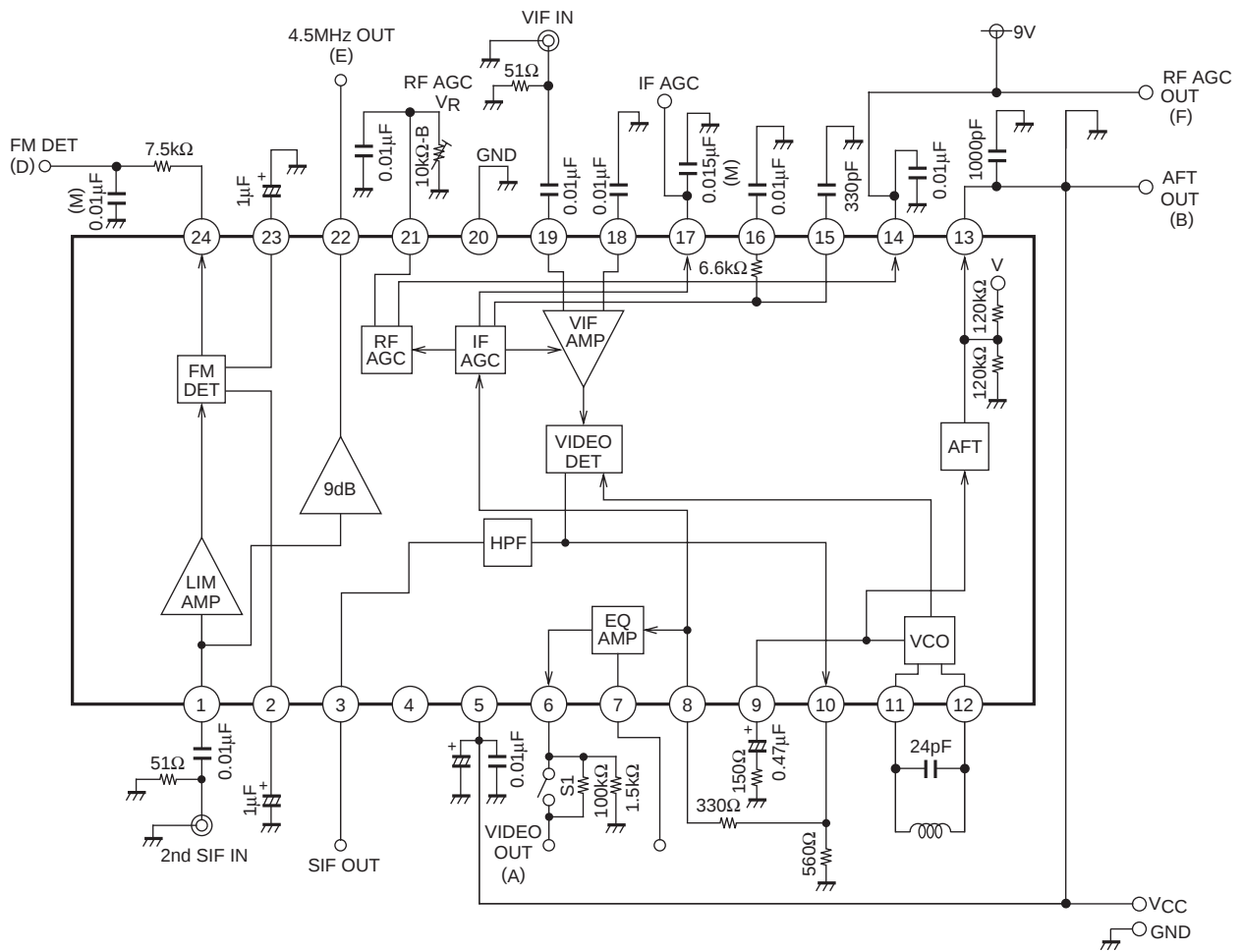


Pin Assignment

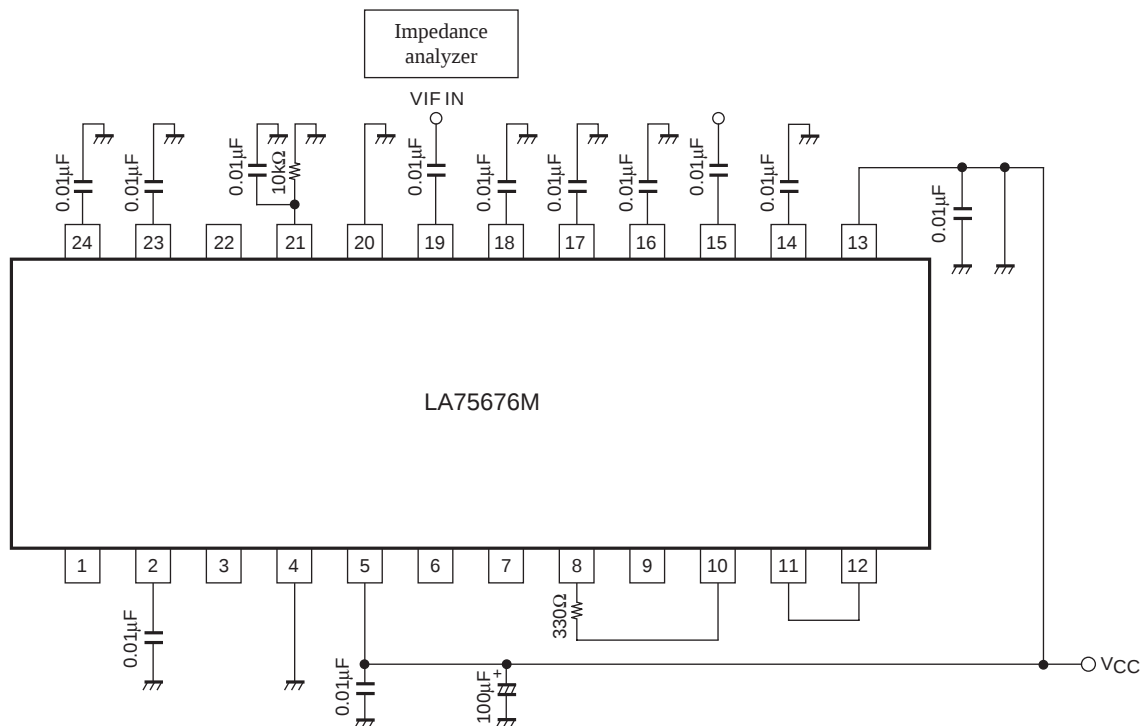


LA75676M

Block Diagram and AC Characteristics Test Circuit



Test Circuit (Input impedance)



Test Conditions**V1. Circuit current •••• [15]**

1. Internal AGC
2. Input a 45.75MHz, 10mVrms, CW signal to the VIF input pin.
3. RF AGC Vr maximum
4. Connect a current meter to V_{CC} and measure the current flowing into the IC.

V2, V3. Maximum RF AGC voltage, minimum RF AGC voltage •••• [V9H, V9L]

1. Internal AGC
2. Input a 45.75MHz, 10mVrms, CW signal to the VIF input pin.
3. Vary the RF AGC Vr and, at the maximum resistance, measure the maximum RF AGC voltage. (F)
4. Vary the RF AGC Vr and, at the minimum resistance, measure the maximum RF AGC voltage. (F)

V4. Input sensitivity •••• [Vi]

1. Internal AGC
2. fp = 45.75MHz, 400Hz 40% AM (VIF input)
3. Set S1 to the off position and pass the input through a 100k Ω resistor.
4. Measure the VIF input level such that the 400Hz detection output level at test point A becomes 0.64Vp-p.

V5. AGC range •••• [GR]

1. External AGC. Apply the V_{CC} voltage to the IF AGC input (pin 17).
2. With the same conditions as used for V4, measure the VIF input level such that the detection output level becomes 0.64Vp-p. ••• Vi1
3. $GR = 20 \log \frac{Vi1}{Vi}$ dB

V6. Maximum allowable input •••• [Vi max]

1. Internal AGC
2. fp = 45.75MHz, 15kHz 78% AM (VIF input)
3. Measure the VIF input level such that the detection output level at test point A is ± 1 dB of the video output (Vo).

V7. Video output voltage (no input) •••• [V6]

1. External AGC. Apply the V_{CC} voltage to the IF AGC input (pin 17).
2. Measure the video output (A) DC voltage.

V8. Sync signal tip voltage •••• [V6tip]

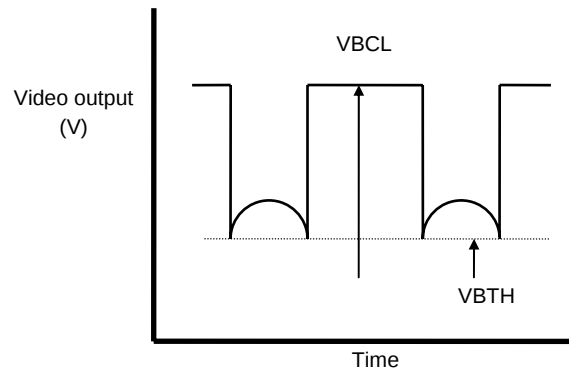
1. Internal AGC
2. Input a 45.75MHz, 10mVrms, CW signal to the VIF input pin.
3. Measure the video output (A) DC voltage.

V9. Video output level •••• [VO]

1. Internal AGC
2. fp = 45.75MHz, 15kHz 78% AM
 $Vi = 10\text{mVrms}$ (VIF input)
3. Measure the wave height of the detection output level at test point A. (Vp-p)

V10, V11. Black noise threshold and clamp voltages •••• [VBTH, VBCL]

1. Apply a DC voltage to the external AGC IF input (pin 17) and vary that voltage.
2. $f_p = 45.75\text{MHz}$, 400Hz, 40% AM, 10mVrms (VIF input)
3. Vary the IF AGC (pin 17) voltage so that the noise canceller operates.
Measure VBTH and VBCL at test point A.



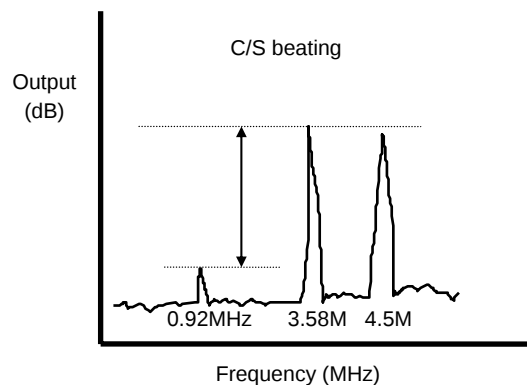
V12. Video signal-to-noise ratio •••• [S/N]

1. Internal AGC
2. $f_p = 45.75\text{MHz}$, CW, 10mVrms (VIF input)
3. Measure the noise voltage as an RMS level at test point A after passing through a 10kHz to 4MHz bandpass filter.
This is the noise voltage (N).

$$4. S/N = 20\log \frac{\text{Video component (Vp-p)}}{\text{Noise voltage (Vrms)}} = 20\log \frac{1.12\text{Vp-p}}{\text{Noise voltage}} = (\text{dB})$$

V13. C/S beating •••• [ICS]

1. Apply a DC voltage to the external AGC IF input (pin 17) and vary that voltage.
2. $f_p = 45.75\text{MHz}$, CW ; 10mVrms
 $f_c = 42.17\text{MHz}$, CW ; 10mVrms - 10dB
 $f_s = 41.25\text{MHz}$, CW ; 10mVrms - 10dB
3. Vary the IF AGC (pin 17) voltage to adjust the output level at test point A to be 1.3Vp-p.
4. Measure the difference in level between the 3.58MHz and the 0.92MHz components at test point A.



V14. Frequency characteristics • • • • [fc]

1. Apply a DC voltage to the external AGC IF input (pin 17) and vary that voltage.
2. SG1 : 45.75MHz, CW, 10mVrms
SG2 : from 45.65MHz to 39.75MHz, CW, 2mVrms
Add SG1 and SG2 using a T pad, adjust the signal generator levels to those listed above, and apply the result to VIF IN.
3. First, set the SG2 frequency to 45.65MHz.
Next, adjust the IF AGC voltage (pin 17) so that the output level at test point A becomes 0.5Vp-p. • • V1
4. Set the SG2 frequency to 39.75MHz and measure the output level. • • V2
5. Perform the following calculation.

$$f_c = 20 \log \frac{V_2}{V_1} \text{ (dB)}$$

V15, V16. Differential gain and differential phase • • • • [DG, DP]

1. Internal AGC
2. fp = 45.75MHz, APL 50%, 87.5% video signal, Vi = 10mVrms
3. Measure DG and DP at test point A.

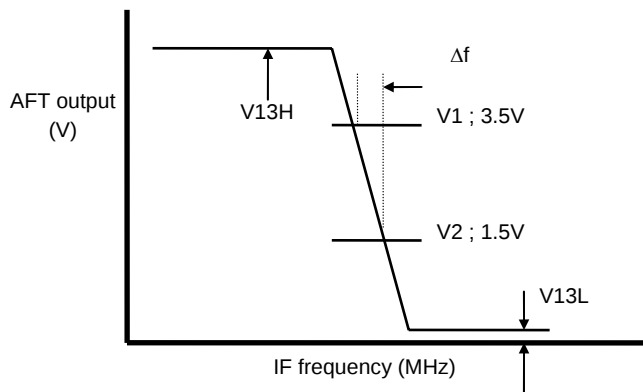
V17. AFT voltage (no signal) • • • • V13

1. Internal AGC
2. Measure the DC voltage on the AFT output (B).

V18, V19, V20. Maximum AFT voltage, minimum AFT voltage, AFT detection sensitivity • • • • [V13H, V13L, Sf]

1. Internal AGC
2. fp = 45.75MHz, ± 1.5 MHz sweep, 10mVrms (VIF input)
3. Record the maximum voltage as V13H and the minimum voltage as V13L.
4. Measure the frequency shift for the change in voltage at test point B from V1 to V2. • • Δf

$$Sf = \frac{2000 \text{ (mV)}}{\Delta f \text{ (kHz)}} \text{ mV/kHz}$$



V21, V22. VIF input resistance, input capacitance • • • • [Ri, Ci]

1. Use an impedance analyzer to measure Ri and Ci in the input impedance test circuit.

V23, V24. APC pull-in range • • • • [fpu, fpl]

1. Internal AGC
2. fp = 39MHz to 51MHz, CW : 10mVrms
3. Vary the signal generator from fp = 45.75MHz towards higher frequencies until PLL lock is lost.
Note : PLL lock is lost at the point beating is output at test point A.
4. Lower the signal generator frequency until the PLL locks again. (f1)
5. Lower the signal generator frequency until PLL lock is lost.
6. Raise the signal generator frequency until the PLL locks again. (f2)
7. Perform the following calculations.
$$f_{pu} = f1 - 45.75\text{MHz}$$
$$f_{pl} = f2 - 45.75\text{MHz}$$

V25. AFT tolerance frequency 1 • • • • [ΔF_{a1}]

1. Internal AGC
2. SG1 : Vary this frequency from 43.75MHz to 47.75MHz, CW, 10mVrms
3. Vary the SG1 frequency so that the AFT output (test point B) becomes 2.5V.
Record the SG1 frequency at that point as f1.
4. External AGC (Adjust V17.)
5. Apply 5V to the IF AGC (pin 17), pick up the VCO oscillator frequency from ground or some other point, and measure that frequency. f2
6. Perform the following calculation.
AFT tolerance frequency 1 $\Delta F_{a1} = f2 - f1$ (kHz)

V26, V27. VCO maximum range (U, L) • • • • [dfu, dfl]

1. External AGC. Apply the VCC voltage to the IF AGC (pin 17).
2. Pick up the VCO oscillator frequency from the video output (A), ground, or some other point and adjust the VCO coil so that frequency becomes 45.75MHz.
3. Apply 1V to the APC pin (pin 9) and let fl be the frequency at that time.
Similarly, apply 5V and let fu be the frequency at that time.
$$dfu = fu - 45.75\text{MHz}$$
$$dfl = fl - 45.75\text{MHz}$$

V28. VCO control sensitivity • • • • [β]

1. External AGC. Apply the VCC voltage to the IF AGC (pin 17).
2. Pick up the VCO oscillator frequency from the video output (A), ground, or some other point and adjust the VCO coil so that frequency becomes 45.75MHz.
3. Apply 3V to the APC pin (pin 9) and let f1 be the frequency at that time.
Similarly, apply 3.4V and let f2 be the frequency at that time.

$$\beta = \frac{f2 - f1}{400} \text{ (kHz/mV)}$$

S1. SIF limiting sensitivity • • • • [Vi (lim)]

1. External AGC. Apply the VCC voltage to the IF AGC (pin 17).
2. fs = 4.5MHz, fm = 400Hz, $\Delta F = \pm 25\text{kHz}$ (SIF input)
3. Set the SIF input level to 100mVrms and measure the value at test point D at that time. • • V1
4. Lower the SIF input level and measure the input level such that V1 is down by 3dB.

S2, S4. FM detection output voltage, total harmonic distortion • • • • [VO(FM), THD]

1. External AGC. Apply the VCC voltage to the IF AGC (pin 17).
2. fs = 4.5MHz, fm = 400Hz, $\Delta F = \pm 25\text{kHz}$ (SIF input, Vi = 100mVrms)
3. Measure the FM detection output voltage and total harmonic distortion at test point D.

S3. AM rejection ratio •••• [AMR]

1. External AGC. Apply the V_{CC} voltage to the IF AGC (pin 17).
2. $f_s = 4.5\text{MHz}$, $f_m = 400\text{Hz}$, $AM = 30\%$ (SIF input, $V_i = 90\text{dB}\mu\text{V}$)
3. Measure the output voltage at test point D. ••• V_{AM}

$$4. AMR = 20\log \frac{V_{O(DET)}}{V_{AM}} \text{ dB}$$

S5. SIF signal-to-noise ratio •••• [S/N]

1. External AGC ($V_{17} = V_{CC}$)
2. $f_s = 4.5\text{MHz}$, no modulation, $V_i = 100\text{mV}_{rms}$
3. Measure the output voltage at test point D. •••• V_n

$$4. S/N = 20\log \frac{V_{O(DET)}}{V_n} \text{ dB}$$

S6. 4.5MHz output level •••• [S/N]

1. External AGC ($V_{17} = V_{CC}$)
2. $f_s = 4.5\text{MHz}$, no modulation, $V_i = 10\text{mV}_{rms}$
3. Measure the output voltage at test point E. •••• V_{sout}

Note 1. Unless specified otherwise, when measuring VIF, apply the V_{CC} voltage to the AGC and adjust the VCO coil so that it oscillates at 45.75MHz.

Note 2. Unless specified otherwise, switch SW1 must be in the on position.

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